

# Quantum Hall effect in $\text{In}_{0.53}\text{Ga}_{0.47}\text{As-InP}$ heterojunctions with two populated electric subbands

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Quantum-Hall-effect and Shubnikov-de Haas measurements are presented for  $\text{In}_x\text{Ga}_{1-x}\text{As-InP}$  heterojunctions with two populated electric subbands and low electron density ( $n_s \leq 5 \times 10^{11} \text{ cm}^{-2}$ ). The Shubnikov-de Haas oscillations clearly show two different periodicities. An anomalous behavior of the quantum Hall effect is observed, in particular some plateaus are missing and other plateaus are enhanced. Precise measurements of the Hall resistance have been performed and it is shown that the resistance of the  $i=2$  plateau is equal to its theoretical value  $h/2e^2$  with an uncertainty of  $\sim 10^{-8}$ .

## I. INTRODUCTION

The quantum Hall effect (QHE) in modulation-doped heterojunctions has stimulated a great many investigations in both  $\text{GaAs-Al}_x\text{Ga}_{1-x}\text{As}$  and  $\text{In}_x\text{Ga}_{1-x}\text{As-InP}$  systems because of the high mobility of the two-dimensional electron gas (2DEG) occurring at the interface. Most of the experiments previously reported were done in heterojunctions (HJ's) in which only the ground electric subband of the 2DEG was populated at low temperature and zero magnetic field. The electron gas is then purely two dimensional; under magnetic field, plateaus in the Hall resistance  $\rho_{xy}$  appear, corresponding with a very high accuracy to the quantized values<sup>1</sup>  $\rho_{xy} = h/ie^2$ , where  $i=1,2,\dots$ , and the minima of the magnetoresistance  $\rho_{xx}$  become simultaneously very small. Values as small as  $\rho_{xx} \sim 5 \times 10^{-7} \Omega/\square$  have been reported.<sup>2</sup> We present here new investigations of the QHE in modulation-doped  $\text{In}_x\text{Ga}_{1-x}\text{As-InP}$  HJ's with two populated electric subbands at zero magnetic field and low electron density  $n_s \leq 5 \times 10^{11} \text{ cm}^{-2}$ . The Shubnikov-de Haas oscillations show two different periodicities which clearly reveal the occupation of two electric subbands in the 2DEG. When the magnetic field is increased, depopulation of the higher subband is observed and corresponds to the reduction of intersubband scattering. An anomalous behavior of the QHE is observed, in particular some plateaus are missing

and other plateaus are enhanced. Precise measurements of the Hall resistance have been performed, and it is shown that the resistance of the  $i=2$  plateau is equal to its theoretical value  $h/2e^2$  in the limit  $\rho_{xx} = 0$ .

The  $\text{In}_{0.53}\text{Ga}_{0.47}\text{As-InP}$  HJ's used here were grown by low-pressure metal-organic chemical-vapor deposition<sup>3</sup> on (100) semi-insulating Fe-doped substrates. The InP layer,  $\sim 1000 \text{ \AA}$  thick, was  $n$  type with  $N_D - N_A \sim 3 \times 10^{15} \text{ cm}^{-3}$ . The  $\text{In}_x\text{Ga}_{1-x}\text{As}$  layer was also  $n$  type with  $N_D - N_A \sim 2 \times 10^{15} \text{ cm}^{-3}$ , its thickness being equal to  $1 \mu\text{m}$ . Electrons are transferred from InP into  $\text{In}_x\text{Ga}_{1-x}\text{As}$  and an accumulation layer is formed at the interface.<sup>4</sup> The mobility of the 2DEG and the electron density at 4 K are obtained from low-field Hall measurements and are listed in Table I for each sample. Standard Hall bridges were used to measure  $\rho_{xx}$  and  $\rho_{xy}$  between 1.3 and 4.2 K. The magnetic field  $B$ , provided by a superconducting coil, could be swept from 0 to 10 T and could be applied either perpendicularly to the interface or tilted by an angle  $\theta$  from the normal to the interface.

## II. EVIDENCE FOR TWO POPULATED SUBBANDS

Figure 1(a) shows the  $B$  dependence of  $\rho_{xx}$  for sample S2 at low magnetic field ( $B < 1 \text{ T}$ ) applied perpendicularly to the interface and  $T = 1.6 \text{ K}$ . Pronounced Shubnikov-de Haas oscillations are observed for  $B > 0.2 \text{ T}$  and two different oscillation periodicities appear clearly, which, we believe, originate from two populated subbands  $E1$  and  $E2$  in the 2DEG. Figure 1(b) gives the reciprocal field corresponding to the oscillation maxima as a function of the Landau-level index. Two linear dependences are observed and are associated with the two periodicities in  $B^{-1}$ . From the slopes of the two linear variations, the population  $n_1 = 4.1 \times 10^{11} \text{ cm}^{-2}$  and  $n_2 = 1.1 \times 10^{11} \text{ cm}^{-2}$  are calculated for  $E1$  and  $E2$ , respectively. The total electron density  $n_1 + n_2 = 5.2$

TABLE I. Characteristics of the heterojunctions used in this work.

Sample	Hall mobility ( $\text{cm}^2/\text{V sec}$ )			$n_s$ ( $\text{cm}^{-2}$ )
	300 K	77 K	4 K	
S1	10 000	50 000	60 000	$4.2 \times 10^{11}$
S2	11 800	55 000	70 000	$5.4 \times 10^{11}$
S3	9500	41 000	55 000	$5.4 \times 10^{11}$

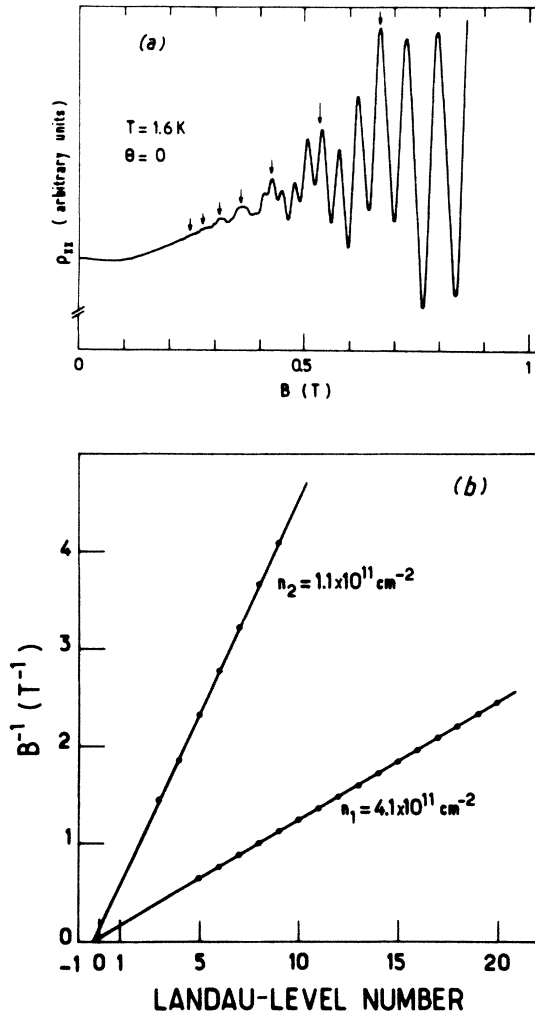


FIG. 1. (a) Shubnikov–de Haas oscillations at low magnetic field ( $B < 1$  T) in sample S2. The maxima of the low-frequency oscillations are indicated by arrows (see text). (b) Reciprocal magnetic field at maxima of the high- and low-frequency oscillations versus the Landau-index number.

$\times 10^{11} \text{ cm}^{-2}$  deduced from the Shubnikov–de Haas data is in good agreement with the value  $n_s = 5.4 \times 10^{11} \text{ cm}^{-2}$  obtained from low-magnetic-field Hall measurements at 4 K in sample S2. Using  $m^* = 0.047m_0$  for the 2DEG effective mass,<sup>4</sup> we get the Fermi energies  $E_{F,1} = 21$  meV and  $E_{F,2} = 5.5$  meV, measured from the bottom of the two subbands E1 and E2, respectively. The subband separation is then  $\sim 15.5$  meV and the higher subband E2 starts to be occupied at  $n_s \sim 3 \times 10^{11} \text{ cm}^{-2}$ . Similar results are obtained in sample S1 ( $n_1 = 3.5 \times 10^{11} \text{ cm}^{-2}$ ,  $n_2 = 0.6 \times 10^{11} \text{ cm}^{-2}$ ) and S3 ( $n_1 = 4.6 \times 10^{11} \text{ cm}^{-2}$ ,  $n_2 = 0.9 \times 10^{11} \text{ cm}^{-2}$ ). However, in previous experiments performed on HJ's grown by the same method, we had observed<sup>4,5</sup> only one occupied subband for  $n_s \sim 4.5 \times 10^{11} \text{ cm}^{-2}$ . On the other hand, two populated subbands were evidenced<sup>6</sup> in  $\text{Al}_x\text{In}_{1-x}\text{As-In}_x\text{Ga}_{1-x}\text{As}$  HJ's grown by molecular-beam epitaxy for  $n_s \gtrsim 4.5 \times 10^{11} \text{ cm}^{-2}$ . The reason why a second subband is occupied for the low

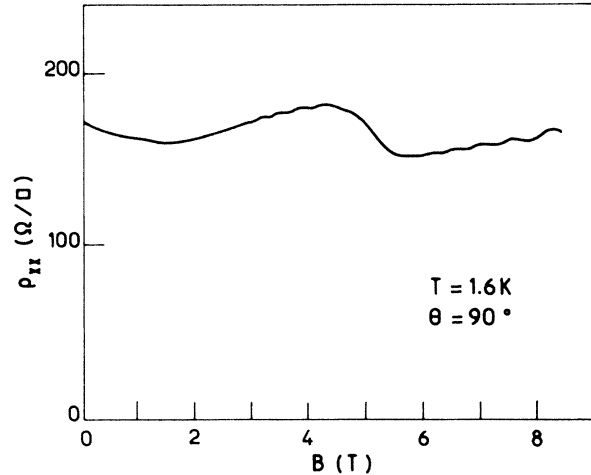


FIG. 2. Magnetoresistance of sample S2 with  $B$  parallel to the interface.

values of  $n_s$  reported here is not yet understood, but we would like to suggest a possible explanation. Indeed, it is important to note that, in the case of an accumulation layer in an  $n$ -type material, the potential profile, i.e., the subband position, is mainly defined at low temperature by the fixed charges which are the minority acceptor impurities.<sup>7</sup> As a result, the subband separation between E2 and E1, and therefore the critical concentration for which E2 becomes occupied, strongly depends on the minority acceptor concentration in the  $\text{In}_x\text{Ga}_{1-x}\text{As}$  layer which is unknown but may vary from sample to sample. If this suggestion is correct, this means that there are fewer acceptors in the  $\text{In}_x\text{Ga}_{1-x}\text{As}$  layers of samples S1, S2, and S3 than in the samples we used in Refs. 4 and 5, so that the HJ's investigated here would be of better quality. This is supported by the fact that, despite the intersubband scattering, the electron mobility in samples S1, S2, and S3 is higher than in our previous heterostructures.<sup>4,5</sup>

The existence of two populated subbands gives rise to intersubband scattering as calculated<sup>8</sup> and observed<sup>9</sup> in  $\text{GaAs-Al}_x\text{Ga}_{1-x}\text{As}$  HJ's. The influence of intersubband scattering can be demonstrated from magnetoresistance experiments with  $B$  parallel to the interface ( $\theta = 90^\circ$ ). The effect of a parallel magnetic field is to increase the subband separation and, finally, to depopulate<sup>10,11</sup> E2. Figure 2 shows the magnetoresistance  $\rho_{xx}$  as a function of  $B$  for  $\theta = 90^\circ$  in sample S2, which exhibits a fall of 20% about in the resistance occurring at  $B \sim 5$  T. This fall corresponds to the magnetic depopulation of the higher subband E2 and to the reduction of the intersubband scattering. Similar results were obtained<sup>12</sup> in  $\text{Al}_x\text{In}_{1-x}\text{As-In}_x\text{Ga}_{1-x}\text{As}$  HJ's and also in the resistance of  $\text{GaAs-Al}_x\text{Ga}_{1-x}\text{As}$  HJ's as a function of the electron concentration.<sup>9</sup>

### III. QUANTUM HALL EFFECT

Figure 3 shows  $\rho_{xx}$  and  $\rho_{xy}$  in sample S1 at 1.3 K as a function of  $B$  applied perpendicularly to the interface. Striking features are observed in  $\rho_{xy}$  as compared to the usual QHE curves reported<sup>5,13</sup> in similar samples with

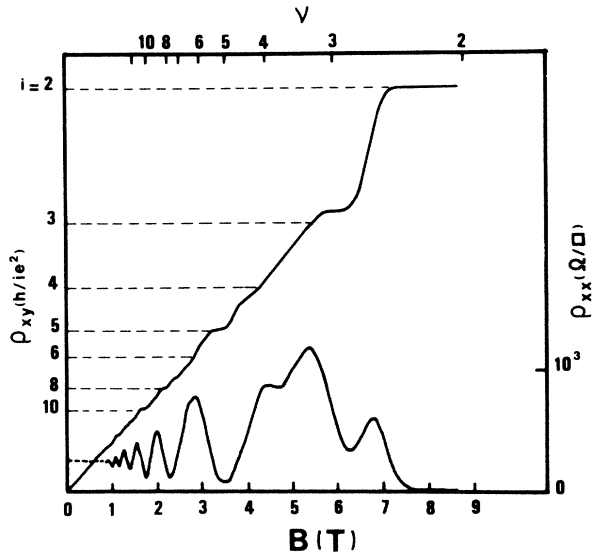


FIG. 3. Hall resistance  $\rho_{xy}$  and magnetoresistance  $\rho_{xx}$  as a function of  $B$  and the filling factor  $\nu$  in sample S1 ( $T=1.3$  K).

only one occupied subband. While the  $i=2, 8,$  and  $10$  plateaus are well developed at  $B \sim 8.5, 2.2,$  and  $1.75$  T, respectively, the  $i=4$  and  $i=6$  plateaus are nearly missing. Moreover, the width of the  $i=5$  plateau occurring at  $B \sim 3.5$  T is anomalous. Indeed, in experiments previously reported<sup>5</sup> on  $\text{In}_x\text{Ga}_{1-x}\text{As-InP}$  HJ's with similar values of  $n_s$  and of the electron mobility but with only one occupied subband, the  $\rho_{xy} = h/5e^2$  plateau was not observed even at very low temperature, because the spin splitting of the  $N=2$  Landau level was not resolved. Remarkable features are also observed in the  $\rho_{xx}$  dependence as a function of the filling factor  $\nu = n_s h / eB$ . Figure 3 shows that  $\rho_{xx}$  minima occur for  $\nu = 2, 5, 8, 10, 12$  but only smaller structures are observed at  $\nu \sim 3, 4, 6$ . Furthermore, the only vanishing  $\rho_{xx}$  minimum occurs at  $\nu = 2$ . The anomalous behavior of  $\rho_{xy}$  can be explained by the existence of two occupied electric subbands at  $B=0$ . Figure 4 shows a schematic diagram of the Landau levels  $N_{\pm}$  and  $N'_{\pm}$  arising from the two occupied subbands  $E1$  and  $E2$ , respectively. The calculations are done for  $\theta=0$  using  $15$  meV as the subband separation,  $m^* \simeq 0.047m_0$ ,<sup>4</sup> and an enhanced Landau factor<sup>13</sup>  $g \sim 10$ , independent of the Landau level index and  $B$ . The resulting variation of the Fermi energy  $E_F$ , assuming infinitely sharp Landau levels, is also shown for a total electron concentration  $n_s = 4.2 \times 10^{11} \text{ cm}^{-2}$ . The middle of each  $\rho_{xy}$  plateau and the  $\rho_{xx}$  minima in Fig. 3 must correspond to vertical jumps of  $E_F$  from one level to the next one occurring for integral values of  $\nu$ . Figure 4 shows that the two Landau levels  $0'_+$  and  $1_-$  overlap in the vicinity of  $\nu=4$  ( $B \sim 4.4$  T), yielding no significant jump of  $E_F$ . This is consistent with the absence of the  $i=4$  plateau in  $\rho_{xy}$  and the observation of a small dip instead of a real minimum in  $\rho_{xx}$  at  $\nu \sim 4$  (Fig. 3). Similarly, the crossover of the  $1_+$  and  $0'_+$  levels in the vicinity of  $\nu=3$  ( $B \sim 5.8$  T) strongly perturbs the  $\rho_{xy}$  plateau occurring at  $B \sim 6$  T whose value is significantly larger than  $h/3e^2$ . The well-developed  $i=5$  pla-

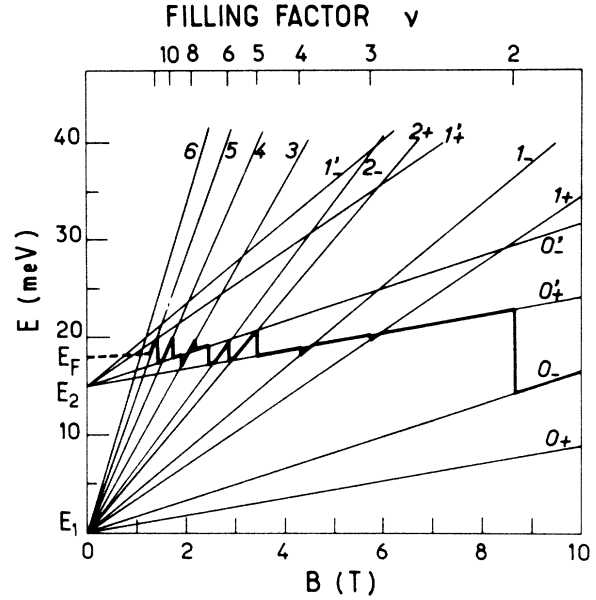


FIG. 4. Schematic diagram of the Landau levels  $N_{\pm}$  and  $N'_{\pm}$  arising from the two ground subbands  $E1$  and  $E2$ . (The subscripts  $+$  and  $-$  refer to spin up and down, respectively.) For the sake of simplicity, the spin splitting of the levels is not presented for  $N \geq 3$ . The variation of the Fermi energy  $E_F$  assuming infinitely sharp Landau levels and a constant electron concentration  $n_s = 4.2 \times 10^{11} \text{ cm}^{-2}$  is also shown (dotted line).

teau appears when the  $0_{\pm}, 1_{\pm},$  and  $0'_+$  Landau levels are completely filled and corresponds to the jump of  $E_F$  from  $0'_+$  to  $0'_-$ . Note that in previous experiments<sup>5,13</sup> in  $\text{In}_x\text{Ga}_{1-x}\text{As-InP}$  HJ's with only one occupied subband, the  $i=5$  plateau would have corresponded to the jump of  $E_F$  between the two  $N=2$  spin components which are not experimentally<sup>5,13</sup> resolved in samples with an electron mobility less than  $70\,000 \text{ cm}^2/\text{V sec}$ .

Figure 4 shows that, in the case of S1, the  $i=6$  plateau would correspond to the spin splitting of  $N=2$  which, again, is not experimentally resolved. This is consistent with the absence of the  $i=6$  plateau in  $\rho_{xy}$  and the nonobservation of any  $\rho_{xx}$  minimum at  $\nu=6$  (Fig. 3). Finally, the  $i=8$  and  $i=10$  plateaus correspond to the usual situation when pairs of spin-split Landau levels are completely filled ( $0_{\pm}, 0'_{\pm}, 1_{\pm}, 2_{\pm}$  for  $i=8$  and  $0_{\pm}, 0'_{\pm}, 1_{\pm}, 2_{\pm}, 3_{\pm}$  for  $i=10$ ). Note that, above  $8.75$  T, the subband  $E2$  is totally depopulated by the magnetic field (Fig. 4). The  $i=2$  plateau and the  $\nu=2$  minimum of  $\rho_{xx}$  in Fig. 3 correspond to the usual situation where only one subband is occupied. A complete redistribution of the energy levels is obtained in tilted magnetic fields ( $\theta \neq 0$ ) since the Landau level separation is determined only by the  $B$  component perpendicular to the interface while the spin splitting comes from the total magnetic field. Figure 5 shows  $\rho_{xy}$  in sample S1 for  $\theta=45^\circ$ . The  $i=4, 5, 6, 10, 12$  plateaus are observed, but the  $i=8$  plateau is now missing. Again the result could be qualitatively interpreted with a schematic diagram of the Landau level arising from the subband  $E1$  and  $E2$  at  $\theta=45^\circ$ . For a more precise analysis of the results, it would be necessary to take into account the

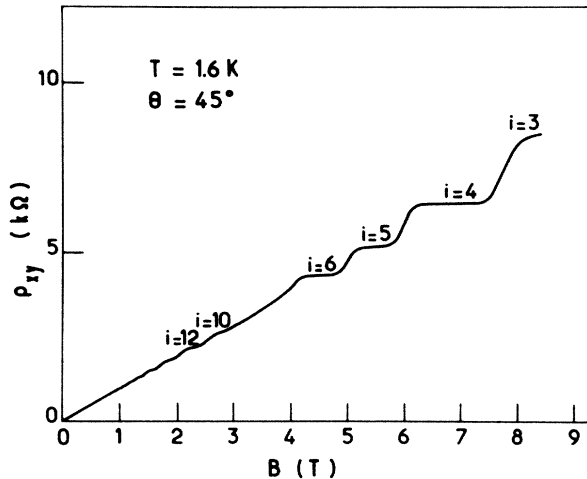


FIG. 5. Quantum Hall effect in tilted magnetic field ( $\theta=45^\circ$ ) in sample S1.

broadening of the Landau levels, the exact dependence of the effective  $g$  factor on  $B$  and  $N$ , and, for  $\theta \neq 0$ , the shift of the  $E1$  and  $E2$  positions due to the introduction of a  $B$  component parallel to the interface.<sup>10,11</sup>

#### IV. PRECISE MEASUREMENT OF THE QUANTIZED HALL RESISTANCE

Precise Hall resistance measurements referred to a standard resistor were made at the Laboratoire Central des In-

dustries Electriques at Fontenay-aux-Roses in France on sample S1. The experimental setup (a specially designed resistance-ratio measurement bridge using a cryogenic current comparator) was described elsewhere<sup>14</sup> and allows experiments with a  $2.2 \times 10^{-8}$  uncertainty ( $1\sigma$ ). The  $i=2$  plateau which is associated with the smallest minimum of  $\rho_{xx}$  ( $\rho_{xx}^{\min} \sim 10^{-3} \Omega/\square$  at 1.3 K), was investigated between 2 and 1.3 K. At 1.3 K, the plateau is flat to better than  $\pm 5 \times 10^{-8}$  over a 0.4-T range. The Hall resistance as a function of  $\rho_{xx}^{\min}$  shows the linear variation:

$$\rho_{xy}(\rho_{xx}^{\min}) = \rho_{xy}(0) + 0.07\rho_{xx}^{\min}.$$

A similar linear law was previously observed<sup>1</sup> in  $\text{GaAs-Al}_x\text{Ga}_{1-x}\text{As}$  HJ's and may be due, at least partly, to the misalignment of the Hall probes. The most interesting result is that the extrapolated value  $\rho_{xy}(0)$  in nondissipative conditions, i.e., at  $\rho_{xx}^{\min}=0$ , is the same, within the experimental uncertainty, as the value obtained on  $\text{GaAs-Al}_x\text{Ga}_{1-x}\text{As}$  HJ's.  $\rho_{xy}(0)$  is expected to be equal to the theoretical value  $h/2e^2$ . At 1.3 K, the correction  $\Delta\rho_{xy}/\rho_{xy}(0)$  due to the finite value of  $\rho_{xx}^{\min}$  is less than  $10^{-8}$ . Detailed information about these precise  $\rho_{xy}$  measurements will be published elsewhere.<sup>15</sup>

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